



FORM PTO-1449		Docket Number (Optional) 294G 1787-5		Application Number 10/027,671	
<b>INFORMATION DISCLOSURE CITATION IN AN APPLICATION</b>		Applicant Colbert et al.			
(Use several sheets if necessary)		Filing Date 12/21/2001		Group Art Unit 1754	
<b>U.S. PATENT DOCUMENTS</b>					
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	FILING DATE IF APPROPRIATE
<b>FOREIGN PATENT DOCUMENTS</b>					
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	TRANSLATION (YES/NO)
	JP H06-331309	12/2/1994	Japan		
	JP H06-252056	9/9/1994	Japan		
	JP H07-122198	5/12/1995	Japan		
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>					
	"Imaging steep, high structures by scanning force microscopy with electron beam deposited tips" by David J. Keller, et al., pages 333-339 in the <i>Surface Science</i> magazine published by Elsevier Science Publishers B.V. in 1992 in Holland				
	"New Scanning tunneling microscopy tip for measuring surface topography" by Y. Akama, et al., pages 429-433 in <i>Vac. Sci. Technol. A 8</i> published by American Vacuum Society in 1990				
	"Atomic force microscopy using ZnO whisker tip" by H. Kado, et al., pages 3330-3332 in <i>Rev. Sci. Instrum</i> 63 published by American Institute of Physics in 1992				
	"Helical microtubules of graphitic carbon" by Sumio Iijima, pages 56-58 in the <i>Nature</i> magazine Vo. 354 published in 1991				
	"Single-shell carbon nanotubes of 1-nm diameter" by Sumio Iijima et al., pages 603-605 in the <i>Nature</i> magazine Vo. 363 published in 1993				
	"Aligned Carbon Nanotube Arrays Formed by Cutting a Polymer Resin-Nanotube Composite" by P.M Ajaya, et al., pages 1212-1214 in the <i>SCIENCE</i> magazine Vo. 265 published in 1994				
	"Aligned Carbon Nanotube Films: Production and Optical and Electronic Properties" by Walt A. de Heer, et al., pages 845-847 in the <i>SCIENCE</i> magazine Vo. 268 published in 1995				
EXAMINER		DATE CONSIDERED			
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.					

Not Considered (After issue fee)